Application/Control No. Reexamination 10/521,943 SUEHIRO ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 David J. Makiya 2885

U.S. PATENT DOCUMENTS							
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification		
*	Α	US-7,086,765 B2	08-2006	Wehner, Kathryn M.	362/511		
*	В	US-7,422,349 B2	09-2008	Wada et al.	362/373		
	υ	US-					
	D	US-					
	Е	US-					
	F	US-					
	G	US-		-			
	Н	US-		-			
	-	US-					
	7	US-					
	К	US-					
	L	US-					
	м	US-					

FOREIGN PATENT DOCUMENTS

	TOTAL						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N						
	0						
	Р						
	Q		l				
	R						
	s						
	Т						

NON-PATENT DOCUMENTS					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	v				
	w				
	x				

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under